



**Form 1449 (Modified)**

**Information Disclosure  
Statement By Applicant**

(Use Several Sheets if Necessary)

Petty Docket No. 11-  
SLAM1P136/P0602  
Applicant:  
HUANG et al.  
Filing Date  
March 30, 2000

Application No.

09/539,313

RECEIVED

AUG 28 2000

Group  
2755

TC 2700 MAIL ROOM

**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A						
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						

**Foreign Patent or Published Foreign Patent Application**

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	J							
	K							
	L							
	M							
	N							

**Other Documents**

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
<i>De</i>	O	U.S. Patent Application No. 09/539,312, filed March 30, 2000, entitled: "Integrated Full Wavelength Spectrometer for Wafer Processing"
	P	
	Q	

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

**Form 1449 (Modified)****Information Disclosure  
Statement By Applicant**

(Use Several Sheets if Necessary)

Atty Docket No. **O I P E** Application No.:  
**LAM1P136/P0602** 09/539,313  
 Applicant: **HUANG et al.** MAY 28 2002  
 Filing Date **03/30/00**  
 Group **2152**

**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A						
	B						
	C						<b>RECEIVED</b>
	D						
	E						<b>MAY 30 2002</b>
	F						
	G						<b>Technology Center 2600</b>
	H						
	I						

**Foreign Patent or Published Foreign Patent Application**

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
<i>DC</i>	J	99 08168 A	18/02/99	WIPO	G05B	23/02	Yes	
<i>DE</i>	K	2 692 701	24/12/93	France	G06F	15/46		No
<i>DE</i>	L	0552 873 A1	28/07/93	EPO	G06F	13/40	Yes	
	M							
	N							

**Other Documents**

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
<i>DC</i>	O	International Search Report, date mailed April 19, 2002
<i>DC</i>	P	Kang B. Lee and Richard D. Schneeman, "Internet-Based Distributed Measurement and Control Applications", IEEE Instrumentation & Measurement Magazine, June 1999, pg. 23-27
	Q	
Examiner	Date Considered <i>David England</i> 3/31/03	

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.